

AZ809A

Pin Configuration

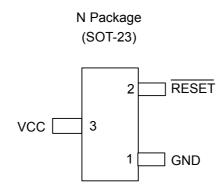


Figure 2. Pin Configuration of AZ809A (Top View)

Pin Description

Pin Number	Pin Name	Function
1	GND	Ground pin
2	RESET	Active low output. The \overline{RESET} is asserted LOW if V_{CC} falls below the reset threshold and remains LOW for the 240ms typical reset timeout period (140ms minimum) after V_{CC} exceeds the threshold
3	VCC	Power supply input voltage (3.0V, 3.3V, 5.0V)



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Functional Block Diagram

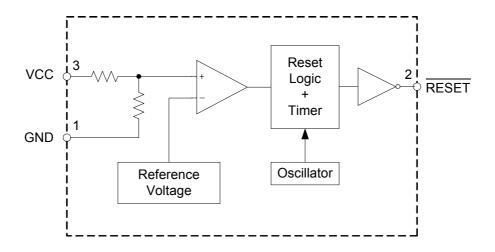
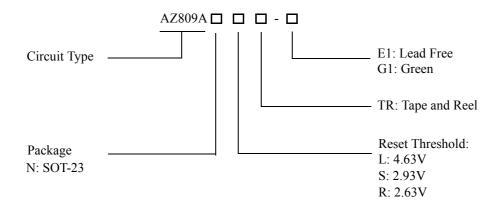


Figure 3. Functional Block Diagram of AZ809A

Ordering Information



Package	Temperature Range T	Reset	Part Number		Marking ID		Packing	
		Threshold	Lead Free	Green	Lead Free	Green	Type	
SOT-23	-40 to 105°C	4.63V	AZ809ANLTR-E1	AZ809ANLTR-G1	EH7	GH7	Tape & Reel	
		2.93V	AZ809ANSTR-E1	AZ809ANSTR-G1	EH1	GH1		
		2.63V	AZ809ANRTR-E1	AZ809ANRTR-G1	ЕН6	GH6		

BCD Semiconductor's Pb-free products, as designated with "E1" suffix in the part number, are RoHS compliant. Products with "G1" suffix are available in green package.

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Absolute Maximum Ratings (Note 1)

Parameter	Symbol	Value	Unit
Supply Voltage	V _{CC}	-0.3 to 6	V
RESET		-0.3 to V _{CC} +0.3	V
Input Current, VCC Pin		20	mA
Output Current, RESET Pin		20	mA
Rate of Rise, V _{CC}		100	V/µs
Continuous Power Dissipation		320	mW
Junction Temperature	T_{J}	150	°C
Storage Temperature	T _{STG}	-65 to 150	°C
Lead Temperature (Soldering, 10sec)	T_{LEAD}	260	°C
ESD (Human Body Model)		6000	V
ESD (Machine Model)		400	V

Note 1: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "Recommended Operating Conditions" is not implied. Exposure to "Absolute Maximum Ratings" for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Min	Max	Unit
Supply Voltage	V_{CC}	1	5.5	V
Operating Ambient Temperature Range	$T_{\mathbf{A}}$	-40	105	°C



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Electrical Characteristics

(V_{CC} is over the full voltage range, T_A =-40°C to 105°C, unless otherwise noted.

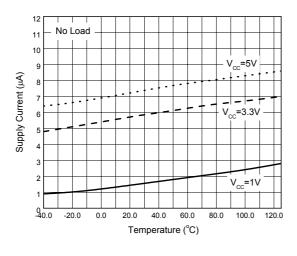
Typical values at T_A =25°C, V_{CC} =5V for L device, V_{CC} =3.3V for S device and V_{CC} =3V for R device.)(Note 2)

Parameter	Symbol	Conditions		Min	Тур	Max	Unit
Input Voltage (V _{CC}) Range	ut Voltage (V_{CC}) Range V_{CC} $T_A=0^{\circ}C$ to $85^{\circ}C$		1.0		5.5	V	
		T_A =-40°C to 105°C		1.2		5.5	Ī , ,
	I _{CC}	L Devices	T_A =-40°C to 85°C, V_{CC} <5.5V		7	11	μА
Supply Current			T_A =-40°C to 105°C, V_{CC} <5.5V			12	
Supply Current		R/S Devices	T_A =-40°C to 85°C, V_{CC} <3.6V		6	10	
			T_A =-40°C to 105°C, V_{CC} <3.6V			11	
			T _A =25°C	4.56	4.63	4.70	V
		L Devices	T_{A} =-40°C to 85°C	4.50		4.75	
	V_{TH}		$T_A = -40^{\circ} \text{C to } 105^{\circ} \text{C}$	4.40		4.86	
		S Devices	$T_A=25^{\circ}C$	2.89	2.93	2.96	
Reset Threshold			T_A =-40°C to 85°C	2.85		3.00	
			$T_A = -40^{\circ} \text{C to } 105^{\circ} \text{C}$	2.78		3.08	
		R Devices	T _A =25°C	2.59	2.63	2.66	
			$T_A = -40^{\circ} \text{C to } 85^{\circ} \text{C}$	2.55		2.70	
			T_A =-40°C to 105°C	2.50		2.76	
Reset Threshold Temperature Coefficient		T _A =-40°C to 105°C			30		ppm/°C
VCC to Reset Delay		V _{CC} =V _{TH} to V _{TH} -100mV			20		μs
Reset Active Timeout Period		$T_A = -40^{\circ} \text{C to}$	85°C	140	240	560	me
Reset Active Timeout Feriod		$T_A = -40^{\circ} \text{C to } 105^{\circ} \text{C}$		100		840	ms
	t Voltage V _{OL}	R/S Devices V _{CC} =V _{TH} (min), I _{SINK} =1.2mA			0.3		
Low RESET Output Voltage		L Devices	V _{CC} =V _{TH} (min), I _{SINK} =3.2mA		0.4		V
Low reader output volume		V _{CC} >1.1V, I _{SINK} =50μA			0.3		1
	age V _{OH}	R/S Devices V _{CC} >V _{TH} (max), I _{SOURCE} =500μA		0.8V _{CC}			
High RESET Output Voltage		L Devices	V _{CC} >V _{TH} (max), I _{SOURCE} =800μA	V _{CC} - 1.5			V

Note 2. Production testing done at T_A=25°C. Over temperature specifications guaranteed by design only.



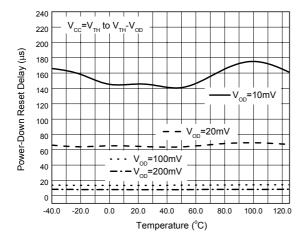
Typical Performance Characteristics



340 Power-up Reset Timeout Period (ms) 320 300 280 240 220 -40.0 -20.0 0.0 20.0 60.0 80.0 100.0 40.0 Temperature (°C)

Figure 4. Supply Current vs. Temperature

Figure 5. Power-up Reset Timeout vs. Temperature



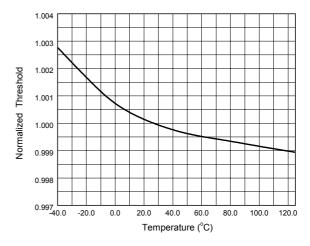


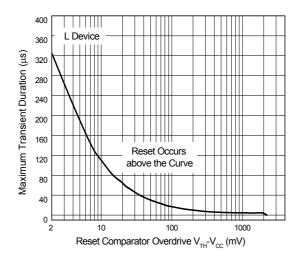
Figure 6. Power-down Reset Delay vs. Temperature

Figure 7. Normalized Reset Threshold vs. Temperature



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Typical Performance Characteristics (Continued)



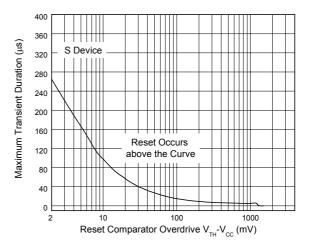


Figure 8. Maximum Transient Duration NOT Causing a Reset Pulse vs. Reset Comparator Overdrive

Figure 9. Maximum Transient Duration NOT Causing a Reset Pulse vs. Reset Comparator Overdrive

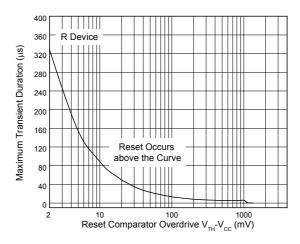
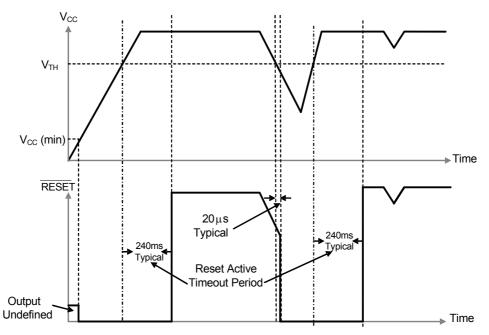


Figure 10. Maximum Transient Duration NOT Causing a Reset Pulse vs. Reset Comparator Overdrive



Operating Diagram



The AZ809A asserts a reset signal LOW whenever the VCC supply voltage is below the threshold voltage and remains asserted for 240ms typically after the VCC has risen above the threshold.

Figure 11. Reset Timing Diagram of AZ809A

Application Information

Valid RESET with V_{CC} under 1.0 V

The AZ809A $\overline{\text{RESET}}$ output is valid to V_{CC} =1.0V. Below this voltage, the output becomes an open circuit and doesn't sink current. Therefore, high-impedance CMOS logic input connected to RESET can drift to undetermined voltages.

To ensure that the AZ809A RESET is in a known state when V_{CC} is under 1.0V, a 100K Ω pull-down resistor between the RESET pin and GND is recommended to discharge stray capacitances and maintain the output low.

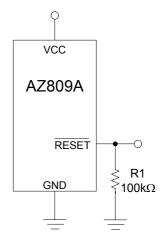


Figure 12. $\overline{\text{RESET}}$ Valid to V_{CC} =0V

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Application Information (Continued)

Negative Going V_{CC} Transient

The AZ809A is optimized to immune fast negative-going transients or glitches on the V_{CC} line, and the sensitivity depends on the duration of the transient and the magnitude of the undershoot below the reset threshold (reset comparator overdrive). Figure 13 shows the maximum pulse width of a negative-going V_{CC} transient that will not cause a reset pulse. As the magnitude of the transient increases (goes farther below the reset threshold), the maximum allowable pulse width decreases. Any combination of duration and overdrive that lies under the curve will not generate a reset signal, typically, a V_{CC} transient that goes 100 mV below the reset threshold and lasts about $20 \mu \text{s}$ or less will not cause a reset pulse.

A $0.1\mu F$ bypass capacitor mounted as close as possible to the V_{CC} pin will provide additional transient rejection.

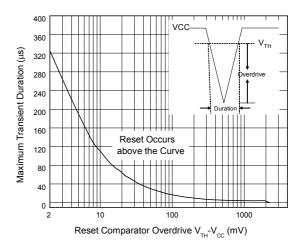


Figure 13. Maximum Transient Duration NOT Causing a Reset Pulse vs. Reset Comparator Overdrive

Typical Application

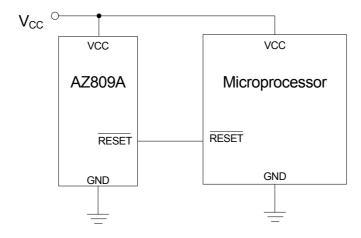


Figure 14. Typical Application of AZ809A

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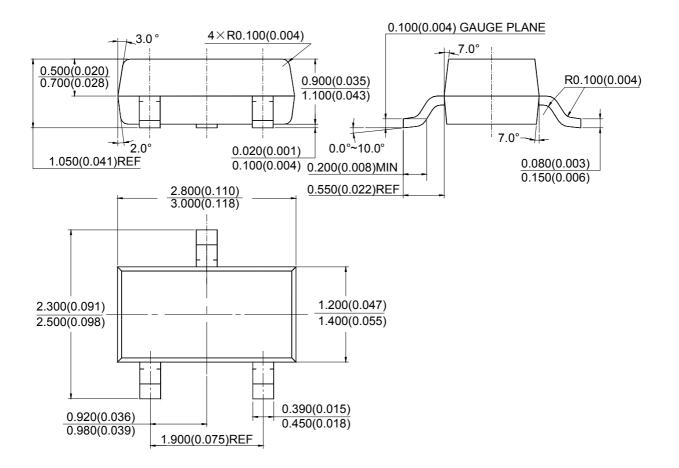
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AZ809A

Mechanical Dimensions

SOT-23 Unit: mm(inch)







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